

Search Notes

Application/Control No.

10/823,613

Examiner

Hieu Nguyen

Applicant(s)/Patent under
Reexamination

WILES ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	308	8/26/2005	HN
330	86	9/7/2005	hn
330	85	9/7/2005	HN
250	214AG	9/7/2005	HN
250	214AG	9/7/2005	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	9/7/2005	HN
NGUYEN KHANH V	9/6/2005	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner